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More Moore's Law through Computational Scaling -- and EDA's Role

David Z. Pan Dept. of Electrical and Computer Engineering The University of Texas at Austin dpan@ece.utexas.edu http://www.cerc.utexas.edu/utda

# **Scaling & Lithography Status**



- 193nm litho continues to push its limit
  - Immersion, extreme RET, DPL (Double Patterning Lithography)
- NGL Next Generation Lithography, still next generation
  - Economical/material/technical challenges

### **A Famous (or Infamous?) Projection**



- Scaling, though challenged, still pushing!
- But more important role in computational scaling

# **Computational Scaling**

- Not just by equipment advancement
- Computational scaling
  - > Scaling enabled by massive computational power
  - > Fast computers to help design faster computers
- Computational lithography for nanolithography systems
  - Computationally reverse-engineering
- Electronic design automation (EDA) eco-system to close the gaps
  - > Synergistic Process-Layout-Circuit Co-Optimization
  - > Parallel, multi-core, GPU, domain-specific, FPGA...

## **Computational Lithography**



#### Other examples:

- > Variational litho-modeling [Yu+, DAC'06, JM3'07]
- > IBM: source mask optimization

## **Computational Nanolithography**

• We do have massive computational power!

- IBM BlueGene, Brion/ASMLTachyon (FPGA acceleration), Gauda (leveraging cheap GPU), ...
- Make a trillion pixels dance [Singh+, SPIE'08]

There's Plenty of Room at the Bottom

- An Invitation to Enter a New Field of Physics



Sti

Richard P. Feynman, 1959

#### Synergistic Process-Layout-Ckt Co-Opt



## **Synergistic Optimizations**



"Give me a lever, and I can optimize your billion transistor design." - EDA's Lever (model/rule)

## **Process Modeling**

How complicated?

 $I_{I}(x_{1}, y_{1}) = \iiint J_{0}(x_{0} - x_{0}, y_{0} - y_{0})F(x_{0}, y_{0})F^{*}(x_{0}, y_{0})$ × $K(x_{1} - x_{0}, y_{1} - y_{0})K^{*}(x_{1} - x_{0}, y_{1} - y_{0})dx_{0}dy_{0}dx_{0}dy_{0}$ 

Litho model: Hopkins eqn

### or simple can it be?

$$Cu\_Thickness = \alpha * (1 - \frac{Metal\_density^2}{\beta})$$

CMP model: [Cho+, ICCAD'06]

### Key Issues:

- Accuracy vs. Fidelity (Elmore-like)
- Design-oriented vs. process-oriented

# **Prediction & Prescription**



- Prediction: e.g., statistical modeling [Cho+, DAC'08], machine learning [Ding+, ICICDT'09]
- Prescription: only work with patterns that are printable

## E.g., Post-OPC Predictive Modeling



Very high macro-level fidelity

### Moving Up: System/High-Level and Logic/Physical-Level Co-design



Variation budgeting with system-level profiling

## **Moving Down: Design for Equipment**

#### **Equipment Characteristics**





#### **Tunable Parameters**

- Timing optimization using ASML dose mapper [Jeong, Kahng+ DAC'08]
- Combine DFM and APC (advanced process control) [Pan+, JPC'08]

## The Moore, The Better

There is still plenty of life for Moore's Law Bigger role of Computational Scaling and EDA to extend the Moore's Law





Moore's Law Amendment [Moore 2003]